

Search Notes

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TAN X. DINH

Applicant(s)/Patent under
Reexamination

ISHII ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

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Interference Search History Printout		11/14/2007	T.D

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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